

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of Applicants:

Beaman et al.

Serial No.: 09/382,834

Filed: August 25, 1999

For: HIGH DENSITY INTEGRATED CIRCUIT APPARATUS, TEST PROBE AND
METHODS OF USE THEREOF

Date: January 14, 2009

Group Art Unit: 2829

Examiner: V. P. Nguyen

Docket No.: YOR919930028US5

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

RESPONSE TO NOTICE OT FILE CORRECTED APPLICATION PAPERS

NOTICE OF ALLOWANCE MAILED DATED 12-11-2008

REMARKS

Enclosed herewith is the corrected sheet of drawings containing Figs. 21 and 22. In the original drawings this sheet had both figures labeled as Fig. 21. On the attached corrected sheet the top Figure is Fig. 21 and the bottom figure is Fig. 22.